- Low Output Skew for Clock-Distribution and Clock-Generation Applications
- State-of-the-Art EPIC-IIB ™ BiCMOS Design Significantly Reduces Power Dissipation
- TTL-Compatible Inputs and CMOS-Compatible Outputs
- Distributes One Clock Input to Six Clock Outputs
- Polarity Control Selects True or Complementary Outputs
- Distributed V_{CC} and GND Pins Reduce Switching Noise
- High-Drive Outputs (–15-mA I_{OH}, 64-mA I_{OL})
- Packaged in Plastic Small-Outline Package

D PACKAGE (TOP VIEW) 16**∏** 1Y1 **GND** 15 1T/C 1Y2 🛮 2 2Y1 3 14 V_{CC} GND [4 ☐ 2 T/C 2Y2 🛮 5 3Y 🛮 6 ∐ ∨<u>c</u>c GND [] 7 10 3T/C 4Y [

description

The CDC329 contains a clock driver circuit that distributes one input signal to six outputs with minimum skew for clock distribution. Through the use of the polarity control inputs (\overline{T}/C) , various combinations of true and complementary outputs can be obtained.

The CDC329 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

INP	JTS	OUTPUT		
T/C	Α	Υ		
L	L	L		
L	Н	Н		
Н	L	Н		
Н	Н	L		

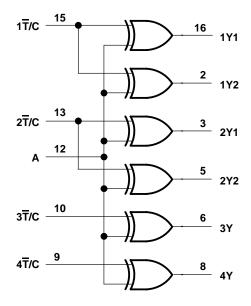
logic symbol†

	12		\triangleright	4	16	4.V4
A 1T/C	15	l		1	2	1Y1
11/C 2T/C	13	N1		1	3	1Y2
21/0		N2		2	5	2Y1
3 T /C	10	No.		2	6	2Y2
4T/C	9	N3		3	8	3Y
41/6		N4		4		4Y

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

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logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC} –0.5 V to	7 V
Input voltage range, V _I (see Note 1)	7 V
Voltage range applied to any output in the high state	
or power-off state, V_O (see Note 1)	.5 V
Current into any output in the low state, I _O	mΑ
Input clamp current, I _{IK} (V _I < 0)	mΑ
Output clamp current, I_{OK} ($V_O < 0$)	mΑ
Continuous total power dissipation at (or below) 25°C free-air temperature (see Note 2) 1000 r	mW
Storage temperature range –65°C to 150	0°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 3)

		MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.75	5	5.25	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			8.0	V
VI	Input voltage	0		VCC	V
lOH	High-level output current			-15	mA
lOL	Low-level output current			64	mA
$\Delta t/\Delta v$	Input transition rise or fall rate			5	ns/V
T _A	Operating free-air temperature	-40		85	°C

NOTE 3: Unused inputs must be held high or low.



NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

^{2.} For operation above 25°C free-air temperature, derate to 478 mW at 85°C at the rate of 8.7 mW/°C.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP [†]	MAX	UNIT
VIK	$V_{CC} = 4.75 \text{ V},$	$I_{I} = -18 \text{ mA}$				-1.2	V
Voн	$V_{CC} = 4.75 \text{ V},$	$I_{OH} = -15 \text{ mA}$		3.85			٧
V _{OL}	$V_{CC} = 4.75 \text{ V},$	$I_{OL} = 64 \text{ mA}$				0.55	V
I _I	$V_{CC} = 5.25 \text{ V},$	$V_I = V_{CC}$ or GND				±1	μΑ
loo	V _{CC} = 5.25 V,	$I_{O} = 0$,	Outputs high			50	μΑ
Icc	$V_I = V_{CC}$ or GND		Outputs low		20	30	mA
C _i	V _I = 2.5 V or 0.5 V				3		pF

 $[\]overline{\dagger}$ All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

switching characteristics over recommended ranges of supply voltage and operating free-air temperature (see Figures 1 and 2)

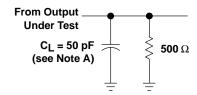
PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	TYP	MAX	UNIT
^t PLH	Δ.	Amir V	2		6.6	ns ns
^t PHL	A	Any Y	1.7		5.4	
^t PLH	Ţ/C	Any Y	1.6		7.4	
t _{PHL}	1/C		1.7		6.3	ns
*	A	Any Y (same phase)			0.5	20
^t sk(o)	A	Any Y (any phase)			2.5	ns
t _r				2		ns
tf				1.3		ns

switching characteristics, V_{CC} = 5 V \pm 0.25 V, T_A = 25°C to 70°C (see Figures 1 and 2)

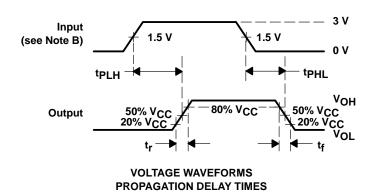
PARAMETER	FROM (INPUT)	TO (OUTPUT)	MIN	MAX	UNIT
t _{PLH}	Δ.	Any Y	2.3	5.9	no
t _{PHL}	A		1.7	4.8	ns
^t sk(o)	Δ.	Any Y (same phase)		0.5	
	А	Any Y (any phase)		2	ns



PARAMETER MEASUREMENT INFORMATION



LOAD CIRCUIT FOR OUTPUTS



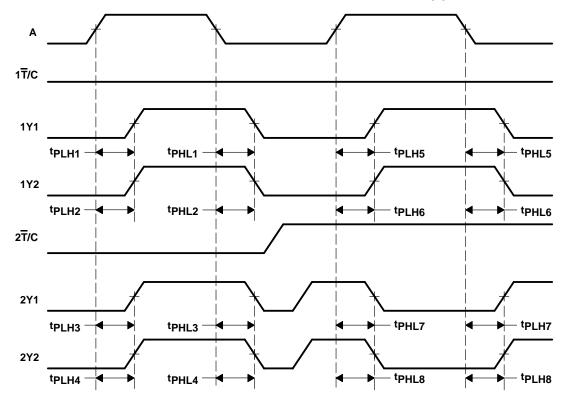
NOTES: A. C_L includes probe and jig capacitance.

B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \ \Omega$, $t_f \leq 2.5 \ ns$, $t_f \leq 2.5 \ ns$.

Figure 1. Load Circuit and Voltage Waveforms



WAVEFORMS FOR CALCULATION OF t_{sk(o)}



Output skew, $t_{sk(0)}$, from A to any Y (same phase), can be measured only between outputs for which the respective polarity control inputs (\overline{T}/C) are at the same logic level. It is calculated as the greater of:

- a) the difference between the fastest and slowest of tp_{LH} from A[↑] to any Y (e.g., tp_{LHn}, n = 1 to 4; or tp_{LHn}, n = 5 to 6),
- b) the difference between the fastest and slowest of tp_{HL} from A↓ to any Y (e.g., tp_{HI} n, n = 1 to 4; or tp_{HI} n, n = 5 to 6),
- c) the difference between the fastest and slowest of tpLH from A↓ to any Y (e.g., tpLHn, n = 7 to 8), and
- d) the difference between the fastest and slowest of tpHL from A↑ to any Y (e.g., tpHLn, n = 7 to 8).

Output skew, $t_{SK(O)}$, from A to any Y (any phase), can be measured between outputs for which the respective polarity control inputs (\overline{T}/C) are at the same or different logic levels. It is calculated as the greater of:

- a) the difference between the fastest and slowest of tp_{LH} from A↑ to any Y or tp_{HL} from A↑ to any Y (e.g., tp_{LHn}, n = 1 to 4; or tp_{LHn}, n = 5 to 6, and tp_{HLn}, n = 7 to 8), and
- b) the difference between the fastest and slowest of tp_{HL} from A↓ to any Y or tp_{LH} from A↓ to any Y (e.g., tp_{HLn}, n = 1 to 4; or tp_{HLn}, n = 5 to 6, and tp_{LHn}, n = 7 to 8).

Figure 2. Skew Waveforms and Calculations



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